

## TWO-DIMENSIONAL SCATTER PLOT TECHNIQUE FOR SEMICONDUCTOR DEFECT INSPECTION

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### Abstract of the Disclosure

10 A method and associated apparatus for relating a  
test image with a reference image in an automated image  
processing system is disclosed. The test and reference  
images are aligned. A two-dimensional scatter plot is  
then created by plotting the gray level of a test image  
pixel against the gray level of a corresponding  
15 reference image pixel for each aligned pixel location.

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